

8GB 1G x 64-Bit DDR4-3200 CL22 1Rx16 260-Pin SODIMM (CBD32D4S2S1ME-8)

Description

This document describes Kingston's 1G x 64-bit (8GB) DDR4-3200 CL22 SDRAM (Synchronous DRAM) 1Rx16, memory module, based on four 1G x 16-bit SDRAMs. This 260-pin SODIMM uses gold contact fingers and requires +1.2V. The electrical and mechanical specifications are as follows:

Feature

- Power Supply: VDD = 1.2V
- VDDQ = 1.2V
- VPP = 2.5V
- VDDSPD = 2.20V to 3.60V
- Functionality and operations comply with the DDR4 SDRAM datasheet
- 16 internal banks (x4, x8): 4 groups of 4 banks each
- 8 internal banks (x16): 2 groups of 4 banks each
- Bank Grouping is applied, and CAS to CAS latency (tCCD_L, tCCD_S) for the banks in the same or different bank group accesses are available
- Data transfer rates: PC4-3200, PC4-2666, PC4-2400, PC4-2133, PC4-1866, PC4-1600
- Bi-Directional Differential Data Strobe
- 8 bit pre-fetch
- Burst Length (BL) switch on-the-fly BL8 or BC4(Burst Chop)
- On-Die Termination (ODT)
- Per DRAM Addressability is supported
- Internal Vref DQ level generation is available
- Write CRC is supported at all speed grades
- DBI (Data Bus Inversion) is supported(x8)
- CA parity (Command/Address Parity) mode is supported
- RoHS Compliant and Halogen-Free
- Gold Finger Plating Au 0.076um (Min)
- Operating Temperature 0° C to +85° C

*Products and specifications discussed herein are for evaluation and reference purposes only and are subject to change by without notice.
All information discussed herein is provided on an "as is" basis, without warranties of any kind.

SODIMM Pin Configuration (Front side/Back side)

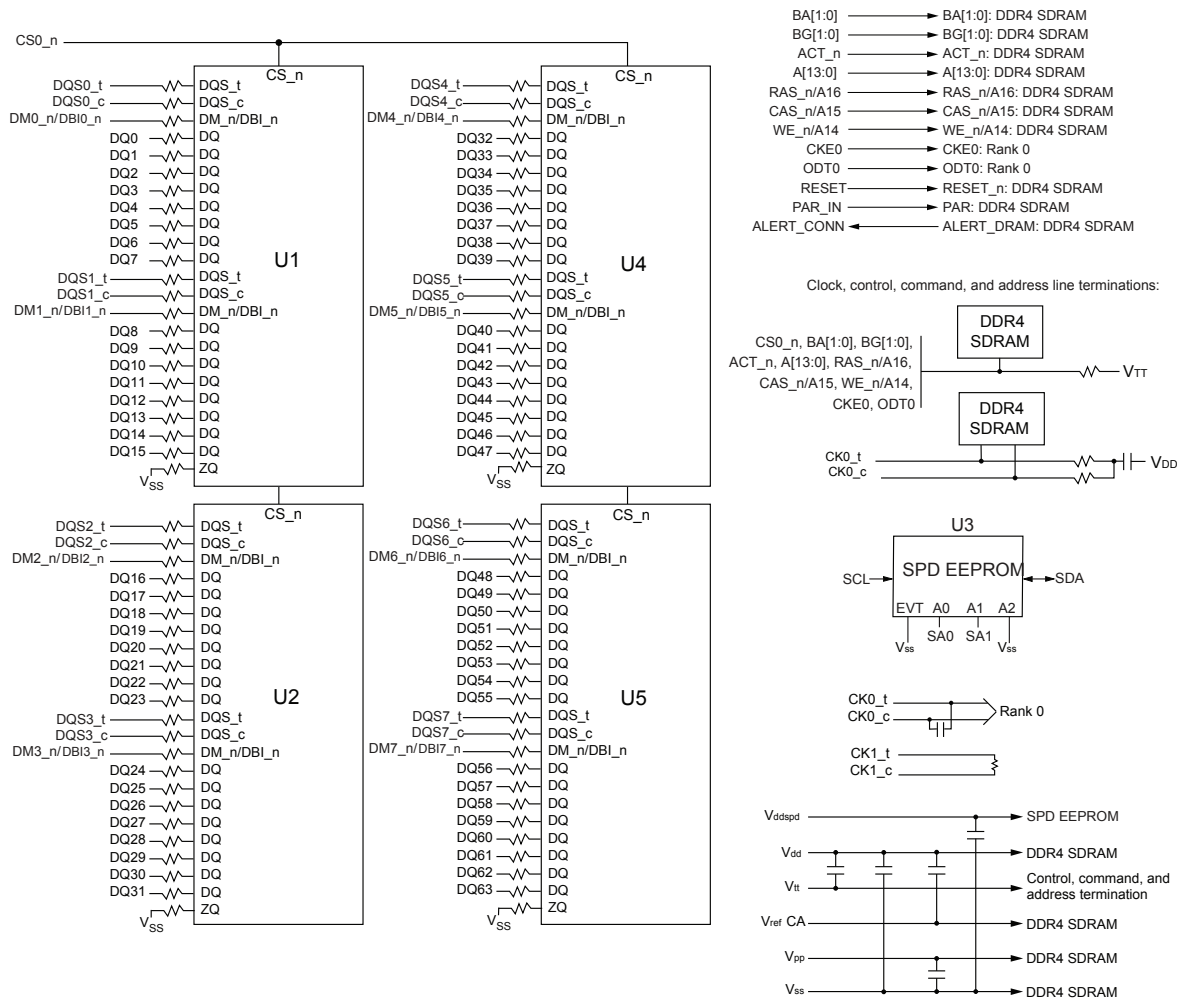
Pin	Front	Pin	Back	Pin	Front	Pin	Back
1	VSS	2	VSS	131	A3	132	A2
3	DQ5	4	DQ4	133	A1	134	EVENT_n
5	VSS	6	VSS	135	VDD	136	VDD
7	DQ1	8	DQ0	137	CK0_t	138	CK1_t
9	VSS	10	VSS	139	CK0_c	140	CK1_c
11	DQS0_c	12	DM0_n/DBI0_n, NC	141	VDD	142	VDD
13	DQS0_t	14	VSS	143	PARITY	144	A0
15	VSS	16	DQ6	KEY			
17	DQ7	18	VSS				
19	VSS	20	DQ2	145	BA1	146	A10/AP
21	DQ3	22	VSS	147	VDD	148	VDD
23	VSS	24	DQ12	149	CS0_n	150	BA0
25	DQ13	26	VSS	151	A14/WE_n	152	A16/RAS_n
27	VSS	28	DQ8	153	VDD	154	VDD
29	DQ9	30	VSS	155	ODT0	156	A15/CAS_n
31	VSS	32	DQS1_c	157	CS1_n	158	A13
33	DM1_n/DBI1_n, NC	34	DQS1_t	159	VDD	160	VDD
35	VSS	36	VSS	161	ODT1	162	C0, CS2_n, NC
37	DQ15	38	DQ14	163	VDD	164	VREFCA
39	VSS	40	VSS	165	C1, CS3_n, NC	166	SA2
41	DQ10	42	DQ11	167	VSS	168	VSS
43	VSS	44	VSS	169	DQ37	170	DQ36
45	DQ21	46	DQ20	171	VSS	172	VSS
47	VSS	48	VSS	173	DQ33	174	DQ32
49	DQ17	50	DQ16	175	VSS	176	VSS
51	VSS	52	VSS	177	DQS4_c	178	DM4_n/DBI4_n, NC
53	DQS2_c	54	DM2_n/DBI2_n, NC	179	DQS4_t	180	VSS
55	DQS2_t	56	VSS	181	VSS	182	DQ39
57	VSS	58	DQ22	183	DQ38	184	VSS
59	DQ23	60	VSS	185	VSS	186	DQ35
61	VSS	62	DQ18	187	DQ34	188	VSS
63	DQ19	64	VSS	189	VSS	190	DQ45
65	VSS	66	DQ28	191	DQ44	192	VSS
67	DQ29	68	VSS	193	VSS	194	DQ41
69	VSS	70	DQ24	195	DQ40	196	VSS
71	DQ25	72	VSS	197	VSS	198	DQS5_c
73	VSS	74	DQS3_c	199	DM5_n/DBI5_n, NC	200	DQS5_t
75	DM3_n/DBI3_n, NC	76	DQS3_t	201	VSS	202	VSS

Pin	Front	Pin	Back	Pin	Front	Pin	Back
77	VSS	78	VSS	203	DQ46	204	DQ47
79	DQ30	80	DQ31	205	VSS	206	VSS
81	VSS	82	VSS	207	DQ42	208	DQ43
83	DQ26	84	DQ27	209	VSS	210	VSS
85	VSS	86	VSS	211	DQ52	212	DQ53
87	CB5, NC	88	CB4, NC	213	VSS	214	VSS
89	VSS	90	VSS	215	DQ49	216	DQ48
91	CB1, NC	92	CB0, NC	217	VSS	218	VSS
93	VSS	94	VSS	219	DQS6_c	220	DM6_n/DBI6_n, NC
95	DQS8_c	96	DM8_n/DBI8_n, NC	221	DQS6_t	222	VSS
97	DQS8_t	98	VSS	223	VSS	224	DQ54
99	VSS	100	CB6, NC	225	DQ55	226	VSS
101	CB2, NC	102	VSS	227	VSS	228	DQ50
103	VSS	104	CB7, NC	229	DQ51	230	VSS
105	CB3, NC	106	VSS	231	VSS	232	DQ60
107	VSS	108	RESET_n	233	DQ61	234	VSS
109	CKE0	110	CKE1	235	VSS	236	DQ57
111	VDD	112	VDD	237	DQ56	238	VSS
113	BG1	114	ACT_n	239	VSS	240	DQS7_c
115	BG0	116	ALERT_n	241	DM7_n/DBI7_n, NC	242	DQS7_t
117	VDD	118	VDD	243	VSS	244	VSS
119	A12	120	A11	245	DQ62	246	DQ63
121	A9	122	A7	247	VSS	248	VSS
123	VDD	124	VDD	249	DQ58	250	DQ59
125	A8	126	A5	251	VSS	252	VSS
127	A6	128	A4	253	SCL	254	SDA
129	VDD	130	VDD	255	VDDSPD	256	SA0
				257	VPP	258	VTT
				259	VPP	260	SA1

Pin Descriptions

Pin Name	Description	Pin Name	Description
A0-A16	SDRAM address bus	SCL	I ² C serial bus clock for SPD/TS
BA0, BA1	SDRAM bank select	SDA	I ² C serial data line for SPD/TS
BG0, BG1	SDRAM bank group select	SA0-SA2	I ² C slave address select for SPD/TS
RAS _n ¹	SDRAM row address strobe	PARITY	SDRAM parity input
CAS _n ²	SDRAM column address strobe	VDD	SDRAM I/O & core power supply
WE _n ³	SDRAM write enable	VPP	SDRAM activating power supply
CS0 _n , CS1 _n , CS2 _n , CS3 _n	Rank Select Lines	C0, C1	Chip ID lines for 3DS components
CKE0, CEK1	SDRAM clock enable lines	VREFCA	SDRAM command/address reference supply
ODT0, ODT1	SDRAM on-die termination control lines	VSS	Power supply return (ground)
ACT _n	SDRAM activate	VDDSPD	Serial SPD/TS positive power supply
DQ0-DQ63	DIMM memory data bus	ALERT _n	SDRAM ALERT _n
CB0-CB7	DIMM ECC check bits		
DQS0 _t -DQS8 _t	SDRAM data strobe (positive line of differential pair)	RESET _n	Set SDRAMs to a Known State
DQS0 _c -DQS8 _c	SDRAM data strobe (negative line of differential pair)	EVENT _n	SPD signals a thermal event has occurred
DM0 _n -DM8 _n , DBI0 _n -DBI8 _n	SDRAM data masks/data bus inversion (x8-based x72 DIMMs)	VTT	Termination supply for the Address, Command and Control bus
CK0 _t , CK1 _t	SDRAM clock (positive line of differential pair)	NC	No connection
CK0 _c , CK1 _c	SDRAM clock (negative line of differential pair)		

Functional Block Diagram



Note: 1. The ZQ ball on each DDR4 component is connected to an external 240 Ω ±1% resistor that is tied to ground. It is used for the calibration of the component's ODT and output driver.

Absolute Maximum DC Ratings

Absolute Maximum DC Ratings

Symbol	Parameter	Rating	Units	NOTE
VDD	Voltage on VDD pin relative to Vss	-0.3 ~ 1.5	V	1,3
VDDQ	Voltage on VDDQ pin relative to Vss	-0.3 ~ 1.5	V	1,3
VPP	Voltage on VPP pin relative to Vss	-0.3 ~ 3.0	V	4
V _{IN} , V _{OUT}	Voltage on any pin relative to Vss	-0.3 ~ 1.5	V	1
T _{STG}	Storage Temperature	-55 to +100	°C	1,2

NOTE :

- Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability
- Storage Temperature is the case surface temperature on the center/top side of the DRAM. For the measurement conditions, please refer to JEDEC51-2 standard.
- VDD and VDDQ must be within 300 mV of each other at all times;and VREFCA must be not greater than 0.6 x VDDQ, When VDD and VDDQ are less than 500 mV; VREF may be equal to or less than 300 mV
- VPP must be equal or greater than VDD/VDDQ at all times

Recommended DC Operating Conditions

Recommended DC Operating Conditions

Symbol	Parameter	Rating			Unit	NOTE
		Min.	Typ.	Max.		
VDD	Supply Voltage	1.14	1.2	1.26	V	1,2,3
VDDQ	Supply Voltage for Output	1.14	1.2	1.26	V	1,2,3
VPP	Supply Voltage for DRAM Activating	2.375	2.5	2.75	V	3

NOTE:

- Under all conditions VDDQ must be less than or equal to VDD.
- VDDQ tracks with VDD. AC parameters are measured with VDD and VDDQ tied together.
- DC bandwidth is limited to 20MHz.

IDD Specifications

Symbol	3200	Units
I_{DD0}	TBD	mA
I_{PP0}	TBD	mA
I_{DD1}	TBD	mA
I_{DD2N}	TBD	mA
I_{DD2NT}	TBD	mA
I_{DD2P}	TBD	mA
I_{DD2Q}	TBD	mA
I_{DD3N}	TBD	mA
I_{PP3N}	TBD	mA
I_{DD3P}	TBD	mA
I_{DD4R}	TBD	mA
I_{DD4W}	TBD	mA
I_{DD5R}	TBD	mA
I_{PP5R}	TBD	mA
I_{DD6N}	TBD	mA
I_{DD6E}	TBD	mA
I_{DD6R}	TBD	mA
$I_{DD6A} (25^{\circ}\text{C})$	TBD	mA
$I_{DD6A} (45^{\circ}\text{C})$	TBD	mA
$I_{DD6A} (75^{\circ}\text{C})$	TBD	mA
$I_{DD6A} (95^{\circ}\text{C})$	TBD	mA
I_{PP6X}	TBD	mA
I_{DD7}	TBD	mA
I_{PP7}	TBD	mA
I_{DD8}	TBD	mA

Electrical Characteristics and AC timing

Refresh Parameters by Device Density

Parameter	Symbol	8Gb	Units
All Bank Refresh to active/refresh cmd time	tRFC1	350	ns
Average periodic refresh interval	tREFI1	0 °C ≤ T _{CASE} ≤ 85°C	7.8 μs
		85 °C < T _{CASE} ≤ 95°C	3.9 μs

Speed Bins and CL, tRCD, tRP, tRC and tRAS for Corresponding Bin

Speed	DDR4-3200	Units	NOTE
Bin (CL - tRCD - tRP)	22-22-22		
Parameter	min		
CL	22	tCK	
tRCD	13.75	ns	
tRP	13.75	ns	
tRAS	32	ns	
tRC	45.75	ns	
tRRDS	5.3	ns	
tFAW	21	ns	

Timing Parameters

Speed								DDR4-3200		Units
Parameter	Symbol							MIN	MAX	
Clock Timing										
Minimum Clock Cycle Time (DLL off mode)	tCK (DLL_OFF)							8	20	ns
Average Clock Period	tCK(avg)							0.625	<0.682	ns
Average high pulse width	tCH(avg)							0.48	0.52	tCK(avg)
Average low pulse width	tCL(avg)							0.48	0.52	tCK(avg)
Absolute Clock Period	tCK(abs)							tCK(avg)min + tJIT(per)min_tot	tCK(avg)max + tJIT(per)max_tot	tCK(avg)
Absolute clock HIGH pulse width	tCH(abs)							0.45	-	tCK(avg)
Absolute clock LOW pulse width	tCL(abs)							0.45	-	tCK(avg)
Clock Period Jitter- total	JIT(per)_tot							-32	32	ps
Clock Period Jitter- deterministic	JIT(per)_dj							-16	16	ps
Clock Period Jitter during DLL locking period	tJIT(per, lck)							-25	25	ps
Cycle to Cycle Period Jitter	tJIT(cc)							-	62	ps
Cycle to Cycle Period Jitter during DLL locking period	tJIT(cc, lck)							-	50	ps
Cumulative error across 2 cycles	tERR(2per)							-46	46	ps
Cumulative error across 3 cycles	tERR(3per)							-55	55	ps
Cumulative error across 4 cycles	tERR(4per)							-61	61	ps
Cumulative error across 5 cycles	tERR(5per)							-65	65	ps
Cumulative error across 6 cycles	tERR(6per)							-69	69	ps
Cumulative error across 7 cycles	tERR(7per)							-73	73	ps
Cumulative error across 8 cycles	tERR(8per)							-76	76	ps
Cumulative error across 9 cycles	tERR(9per)							-78	78	ps
Cumulative error across 10 cycles	tERR(10per)							-80	80	ps
Cumulative error across 11 cycles	tERR(11per)							-83	83	ps
Cumulative error across 12 cycles	tERR(12per)							-84	84	ps
Cumulative error across 13 cycles	tERR(13per)							-86	86	ps
Cumulative error across 14 cycles	tERR(14per)							-87	87	ps
Cumulative error across 15 cycles	tERR(15per)							-89	89	ps
Cumulative error across 16 cycles	tERR(16per)							-90	90	ps
Cumulative error across 17 cycles	tERR(17per)							-92	92	ps
Cumulative error across 18 cycles	tERR(18per)							-93	93	ps
Cumulative error across n = 13, 14 . . . 49, 50 cycles	tERR(nper)							$tERR(nper)min = ((1 + 0.68ln(n)) * tJIT(per)_total min)$ $tERR(nper)max = ((1 + 0.68ln(n)) * tJIT(per)_total max)$		ps
Command and Address setup time to CK_t, CK_c referenced to Vih(ac) / Vil(ac) levels	tIS(base)							40	-	ps
Command and Address setup time to CK_t, CK_c referenced to Vref levels	tIS(Vref)							130	-	ps
Command and Address hold time to CK_t, CK_c referenced to Vih(dc) / Vil(dc) levels	tIH(base)							65	-	ps
Command and Address hold time to CK_t, CK_c referenced to Vref levels	tIH(Vref)							130	-	ps
Control and Address Input pulse width for each input	tIPW							340	-	ps

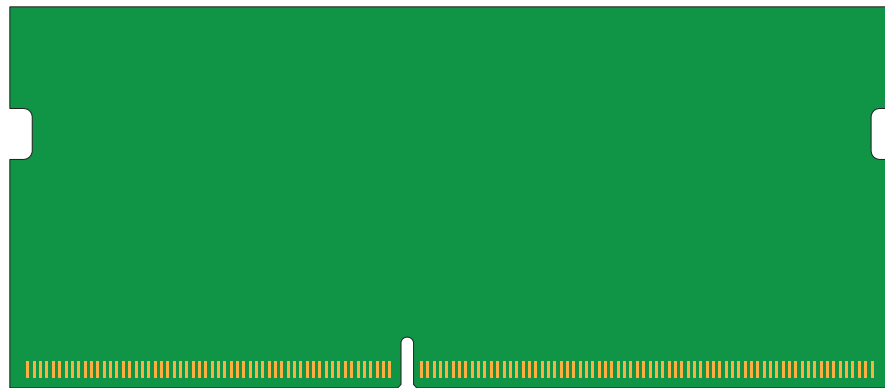
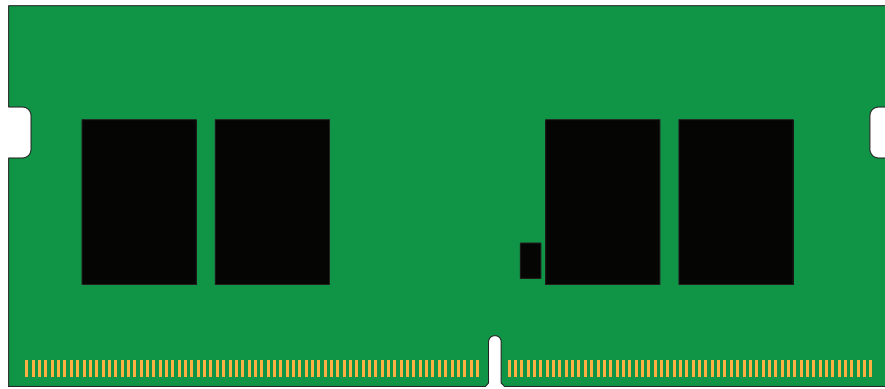
Speed								DDR4-3200		Units	
Parameter	Symbol					MIN	MAX				
Command and Address Timing											
CAS_n to CAS_n command delay for same bank group	tCCD_L							max(5 nCK, 5 ns)	-	nCK	
CAS_n to CAS_n command delay for different bank group	tCCD_S							4	-	nCK	
ACTIVATE to ACTIVATE Command delay to different bank group for 2KB page size	tRRD_S(2K)							Max(4nCK, 5.3ns)	-	nCK	
ACTIVATE to ACTIVATE Command delay to different bank group for 2KB page size	tRRD_S(1K)							Max(4nCK, 2.5ns)	-	nCK	
ACTIVATE to ACTIVATE Command delay to different bank group for 1/2KB page size	tRRD_S(1/2K)							Max(4nCK, 2.5ns)	-	nCK	
ACTIVATE to ACTIVATE Command delay to same bank group for 2KB page size	tRRD_L(2K)							Max(4nCK, 6.4ns)	-	nCK	
ACTIVATE to ACTIVATE Command delay to same bank group for 1KB page size	tRRD_L(1K)							Max(4nCK, 4.9ns)	-	nCK	
ACTIVATE to ACTIVATE Command delay to same bank group for 1/2KB page size	tRRD_L(1/2K)							Max(4nCK, 4.9ns)	-	nCK	
Four activate window for 2KB page size	tFAW_2K							Max (28nCK,30ns)	-	ns	
Four activate window for 1KB page size	tFAW_1K							Max (20nCK, 21ns)	-	ns	
Four activate window for 1/2KB page size	tFAW_1/2K							Max (16nCK, 10ns)	-	ns	
Delay from start of internal write transaction to internal read command for different bank group	tWTR_S							max (2nCK, 2.5ns)	-	ns	
Delay from start of internal write transaction to internal read command for same bank group	tWTR_L							max (4nCK,7.5ns)	-		
Internal READ Command to PRECHARGE Command delay	tRTP							max (4nCK,7.5ns)	-		
WRITE recovery time	tWR							15	-	ns	
Write recovery time when CRC and DM are enabled	tWR_CRC_DM							tWR+max (5nCK,3.75ns)	-	ns	
delay from start of internal write transaction to internal read command for different bank groups with both CRC and DM enabled	tWTR_S_CRC_DM							tWTR_S+max (5nCK,3.75ns)	-	ns	
delay from start of internal write transaction to internal read command for same bank group with both CRC and DM enabled	tWTR_L_CRC_DM							tWTR_L+max (5nCK,3.75ns)	-	ns	
DLL locking time	tDLLK							1024	-	nCK	
Mode Register Set command cycle time	tMRD							8	-	nCK	
Mode Register Set command update delay	tMOD							max(24nCK, 15ns)	-	nCK	
Multi-Purpose Register Recovery Time	tMPRR							1	-	nCK	
Multi Purpose Register Write Recovery Time	tWR_MPR							tMOD (min) + AL + PL	-	nCK	
Auto precharge write recovery + precharge time	tDAL(min)	Programmed WR + roundup (tRP / tCK(avg))									nCK
DQ0 or DQL0 driven to 0 set-up time to first DQS rising edge	tPDA_S							0.5	-	UI	
DQ0 or DQL0 driven to 0 hold time from last DQS falling edge	tPDA_H							0.5	-	UI	
CS_n to Command Address Latency											
CS_n to Command Address Latency	tCAL							max(3 nCK, 3.748 ns)	-	nCK	
Mode Register Set command cycle time in CAL mode	tMRD_tCAL							tMOD+tCAL	-	nCK	
Mode Register Set update delay in CAL mode	tMOD_tCAL							tMOD+tCAL	-	nCK	

Speed								DDR4-3200		Units
Parameter	Symbol						MIN	MAX		
DRAM Data Timing										
DQS _t , DQS _c to DQ skew, per group, per access	tDQSQ						-	0.20	tCK(avg)/2	
DQ output hold time per group, per access from DQS _t , DQS _c	tQH						0.70	-	tCK(avg)/2	
Data Valid Window per device per UI : (tQH - tDQSQ) of each UI on a given DRAM	tDVWd						0.64	-	UI	
Data Valid Window per pin per UI : (tQH - tDQSQ) each UI on a pin of a given DRAM	tDVWp						0.72	-	UI	
DQ low impedance time from CK _t , CK _c	tLZ(DQ)						-250	160	ps	
DQ high impedance time from CK _t , CK _c	tHZ(DQ)						-	160	ps	
Data Strobe Timing										
DQS _t , DQS _c differential READ Preamble (1 clock preamble)	tRPRE						0.9	NOTE 44	tCK	
DQS _t , DQS _c differential READ Preamble (2 clock preamble)	tRPRE2						1.8	NOTE 44	tCK	
DQS _t , DQS _c differential READ Postamble	tRPST						0.33	NOTE 45	tCK	
DQS _t , DQS _c differential output high time	tQSH						0.4	-	tCK	
DQS _t , DQS _c differential output low time	tQSL						0.4	-	tCK	
DQS _t , DQS _c differential WRITE Preamble (1 clock preamble)	tWPRE						0.9	-	tCK	
DQS _t , DQS _c differential WRITE Preamble (2 clock preamble)	tWPRE2						1.8	-	tCK	
DQS _t , DQS _c differential WRITE Postamble	tWPST						0.33	-	tCK	
DQS _t and DQS _c low-impedance time (Referenced from RL-1)	tLZ(DQS)						-250	160	ps	
DQS _t and DQS _c high-impedance time (Referenced from RL+BL/2)	tHZ(DQS)						-	160	ps	
DQS _t , DQS _c differential input low pulse width	tDQSL						0.46	0.54	tCK	
DQS _t , DQS _c differential input high pulse width	tDQSH						0.46	0.54	tCK	
DQS _t , DQS _c rising edge to CK _t , CK _c rising edge (1 clock preamble)	tDQSS						-0.27	0.27	tCK	
DQS _t , DQS _c rising edge to CK _t , CK _c rising edge (2 clock preamble)	tDQSS2						-0.50	0.50	tCK	
DQS _t , DQS _c falling edge setup time to CK _t , CK _c rising edge	tDSS						0.18	-	tCK	
DQS _t , DQS _c falling edge hold time from CK _t , CK _c rising edge	tDSH						0.18	-	tCK	
DQS _t , DQS _c rising edge output timing location from rising CK _t , CK _c with DLL On mode	tDQSCK (DLL On)						-160	160	ps	
DQS _t , DQS _c rising edge output variance window per DRAM	tDQSCKI (DLL On)						-	260	ps	
MPSM Timing										
Command path disable delay upon MPSM entry	tMPED						tMOD(min) + tCPDED(min)	-		
Valid clock requirement after MPSM entry	tCKMPE						tMOD(min) + tCPDED(min)	-		
Valid clock requirement before MPSM exit	tCKMPX						tCKSRX(min)	-		
Exit MPSM to commands not requiring a locked DLL	tXMP						tXS(min)	-		
Exit MPSM to commands requiring a locked DLL	tXMPDLL						tXMP(min) + tXSDLL(min)	-		
CS setup time to CKE	tMPX_S						tISmin + tHmin	-		

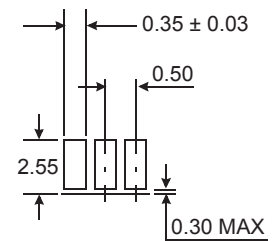
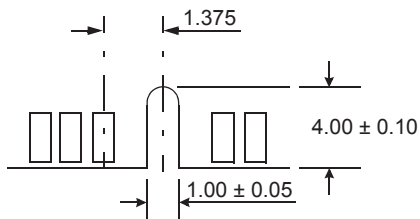
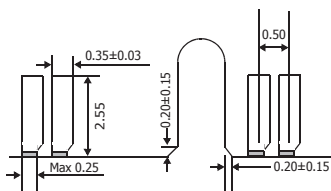
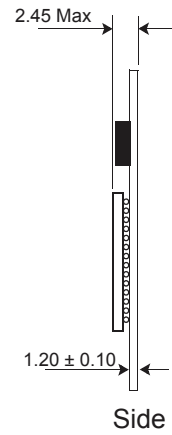
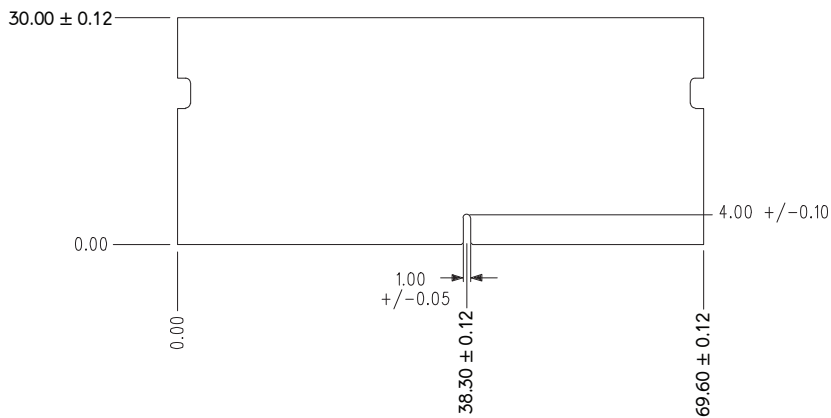
Speed							DDR4-3200		Units
Parameter	Symbol					MIN	MAX		
Calibration Timing									
Power-up and RESET calibration time	tZQinit					1024	-	nCK	
Normal operation Full calibration time	tZQoper					512	-	nCK	
Normal operation Short calibration time	tZQCS					128	-	nCK	
Reset/Self Refresh Timing									
Exit Reset from CKE HIGH to a valid command	tXPR					max(5nCK, tRFC(min)+10ns)	-	nCK	
Exit Self Refresh to commands not requiring a locked DLL	tXS					tRFC(min)+10ns	-	nCK	
SRX to commands not requiring a locked DLL in Self Refresh ABORT	tXS_ABORT(min)					tRFC4(min)+10ns	-	nCK	
Exit Self Refresh to ZQCL, ZQCS and MRS (CL, CWL, WR, RTP and Gear Down)	tXS_FAST(min)					tRFC4(min)+10ns	-	nCK	
Exit Self Refresh to commands requiring a locked DLL	tXSDLL					tDLLK(min)	-	nCK	
Minimum CKE low width for Self refresh entry to exit timing	tCKESR					tCKE(min)+1nCK	-	nCK	
Minimum CKE low width for Self refresh entry to exit timing with CA Parity enabled	tCKESR_PAR					tCKE(min)+1nCK+PL	-	nCK	
Valid Clock Requirement after Self Refresh Entry (SRE) or Power-Down Entry (PDE)	tCKSRE					max(5nCK, 10ns)	-	nCK	
Valid Clock Requirement after Self Refresh Entry (SRE) or Power-Down when CA Parity is enabled	tCKSRE_PAR					max(5nCK, 10ns)+PL	-	nCK	
Valid Clock Requirement before Self Refresh Exit (SRX) or Power-Down Exit (PDX) or Reset Exit	tCKSRX					max(5nCK, 10ns)	-	nCK	
Power Down Timing									
Exit Power Down with DLL on to any valid command; Exit Precharge Power Down with DLL frozen to commands not requiring a locked DLL	tXP					max(4nCK, 6ns)	-	nCK	
CKE minimum pulse width	tCKE					max(3nCK, 5ns)	-	nCK	
Command pass disable delay	tCPDED					4	-	nCK	
Power Down Entry to Exit Timing	tPD					tCKE(min)	9*tREFI	nCK	
Timing of ACT command to Power Down entry	tACTPDEN					2	-	nCK	
Timing of PRE or PREA command to Power Down entry	tPRPDEN					2	-	nCK	
Timing of RD/RDA command to Power Down entry	tRDPDEN					RL+4+1	-	nCK	
Timing of WR command to Power Down entry (BL8OTF, BL8MRS, BC4OTF)	tWRPDEN					WL+4+(tWR/tCK(avg))	-	nCK	
Timing of WRA command to Power Down entry (BL8OTF, BL8MRS, BC4OTF)	tWRAPDEN					WL+4+WR+1	-	nCK	
Timing of WR command to Power Down entry (BC4MRS)	tWRPBC4DEN					WL+2+(tWR/tCK(avg))	-	nCK	
Timing of WRA command to Power Down entry (BC4MRS)	tWRAPBC4DEN					WL+2+WR+1	-	nCK	
Timing of REF command to Power Down entry	tREFPDEN					2	-	nCK	
Timing of MRS command to Power Down entry	tMRSPDEN					tMOD(min)	-	nCK	
PDA Timing									
Mode Register Set command cycle time in PDA mode	tMRD_PDA					max(16nCK, 10ns)	-	nCK	
Mode Register Set command update delay in PDA mode	tMOD_PDA					tMOD		nCK	
ODT Timing									
Asynchronous RTT turn-on delay (Power-Down with DLL frozen)	tAONAS					1.0	9.0	ns	
Asynchronous RTT turn-off delay (Power-Down with DLL frozen)	tAOFAS					1.0	9.0	ns	
RTT dynamic change skew	tADC					0.26	0.74	tCK(avg)	

Speed								DDR4-3200		Units	
Parameter	Symbol					MIN	MAX				
Write Leveling Timing											
First DQS_t/DQS_n rising edge after write leveling mode is programmed	tWLMRD							40	-	nCK	
DQS_t/DQS_n delay after write leveling mode is programmed	tWLDQSEN							25	-	nCK	
Write leveling setup time from rising CK_t, CK_c crossing to rising DQS_t/DQS_n crossing	tWLS							0.13	-	tCK(avg)	
Write leveling hold time from rising DQS_t/DQS_n crossing to rising CK_t, CK_c crossing	tWLH							0.13	-	tCK(avg)	
Write leveling output delay	tWLO							0	9.5	ns	
Write leveling output error	tWLOE							0	2	ns	
CA Parity Timing											
Commands not guaranteed to be executed during this time	tPAR_UNKN OWN							-	PL	nCK	
Delay from errant command to ALERT_n assertion	tPAR_ALERT _ON							-	PL+6ns	nCK	
Pulse width of ALERT_n signal when asserted	tPAR_ALERT _PW							96	192	nCK	
Time from when Alert is asserted till controller must start providing DES commands in Persistent CA parity mode	tPAR_ALERT _RSP							-	85	nCK	
Parity Latency	PL							6		nCK	
CRC Error Reporting											
CRC error to ALERT_n latency	tCRC_ALERT							3	13	ns	
CRC ALERT_n pulse width	CRC_ALERT _PW							6	10	nCK	
Speed								DDR4-3200		Units	
Parameter	Symbol							MIN	MAX		
Geardown timing											
Exit RESET from CKE HIGH to a valid MRS geardown (T2/Reset)	tXPR_GEAR							tXPR	-		
CKE High Assert to Gear Down Enable time(T2/CKE)	tXS_GEAR							tXS	-		
MRS command to Sync pulse time(T3)	tSYNC_GEA R							tMOD+4nCK	-		
Sync pulse to First valid command(T4)	tCMD_GEAR							tMOD	-		
Geardown setup time	tGEAR_setup							2	-	nCK	
Geardown hold time	tGEAR_hold							2	-	nCK	
tREFI											
tRFC1 (min)	2Gb							160	-	ns	
	4Gb							260	-	ns	
	8Gb							350	-	ns	
	16Gb								550 (default)	-	ns
									450 (optional-1)		ns
								350 (optional-2)		ns	
tRFC2 (min)	2Gb							110	-	ns	
	4Gb							160	-	ns	
	8Gb							260	-	ns	
	16Gb								350 (default)	-	ns
									350 (optional-1)		ns
								260 (optional-2)		ns	
tRFC4 (min)	2Gb							90	-	ns	
	4Gb							110	-	ns	
	8Gb							160	-	ns	
	16Gb								260 (default)	-	ns
									260 (optional-1)		ns
								160 (optional-2)		ns	

PACKAGE DIMENSIONS



All measurements are in millimeters.
(Tolerances on all dimensions are ± 0.12 unless otherwise specified)



SPD Content

Byte	Function Described	Function Supported	Hex Value
0	Number of Bytes Used / Number of Bytes in SPD Device / CRC Coverage	512Bytes Total, 384Bytes Used	23
1	SPD Revision	Ver 1.1	11
2	Key Byte / DRAM Device Type	DDR4 SDRAM	0C
3	Key Byte / Module Type	SODIMM	03
4	SDRAM Density and Banks	16Gb, 2BG&4Banks	46
5	SDRAM Addressing	Row bits 17, Column bits 10	29
6	SDRAM Device Type	Monolithic Device	00
7	SDRAM Optional Features	Unlimited MAC	08
8	SDRAM Thermal and Refresh Option	Reserved	00
9	Other SDRAM Optional Features	PPR supported	60
10	Reserved	Reserved	00
11	Module Nominal Voltage, VDD	1.2V	03
12	Module Organization	1Rx16	02
13	Module Memory Bus Width	LP/x64	03
14	Module Thermal Sensor	Thermal sensor not incorporated	00
15-16	Reserved	Reserved	00
17	Timebases	MTB 125ps, FTB 1ps	00
18	SDRAM Minimum Cycle Time(tckavg min)	0.625ns	05
19	SDRAM Minimum Cycle Time(tckavg max)	1.6ns	0D
20	Cas Latency Supported, First Byte	14, 13, 12, 11, 10	F8
21	Cas Latency Supported, Second Byte	22, 21, 20, 19,18, 17, 16, 15	FF
22	Cas Latency Supported, Third Byte	24	02
23	Cas Latency Supported, Fourth Byte		00
24	Minimum Cas Latency Time (tAamin)	13.75ns	6E
25	Minimum RAS to CAS Delay Time(tRCD min)	13.75ns	6E
26	Minimum Raw Precharge Delay Time(tRP min)	13.75ns	6E
27	Upper Nibbles for tRASmin and tRCmin	32ns / 45.75ns	11
28	Minimum Active to Precharge Delay Time (tRASmin), Least Significant Byte	32ns	00
29	Minimum Active to Active/Refresh Delay Time (tRCmin), Least Significant Byte	45.75ns	6E
30	Minimum Refresh Recovery Delay Time (tRFC1min), LSB	350ns	F0
31	Minimum Refresh Recovery Delay Time (tRFC1min), MSB	350ns	0A
32	Minimum Refresh Recovery Delay Time (tRFC2min), LSB	260ns	20
33	Minimum Refresh Recovery Delay Time (tRFC2min), MSB	260ns	08
34	Minimum Refresh Recovery Delay Time (tRFC4min), LSB	160ns	00
35	Minimum Refresh Recovery Delay Time (tRFC4min), MSB	160ns	05
36	Minimum Four Active Window Time (tFAWmin), Most Significant Nibble	21ns	00
37	Minimum Four Activate Window Time (tFAWmin), Least Significant Byte	21ns	F0
38	Minimum Active to Active Delay Time (tRRD_smin), different Bank Group	5.3ns	2B
39	Minimum Active to Active Delay Time (tRRD_Lmin), Same Bank Group	6.4ns	34
40	Minimum CAS to CAS Delay Time(tCCD_Lmin), same bank group	5.0ns	28

SPD Content(cont)

Byte	Function Described	Function Supported	Hex Value
41	Upper Nibble for tWRmin	15ns	00
42	Minimum Write Recovery Time(tWRmin)	15ns	78
43	Upper Nibbles for tWTRmin	7.5ns / 2.5ns	00
44	Minimum Write to Read Time(tWTR_smin), different bank group	2.5ns	14
45	Minimum Write to Read Time(tWTR_Lmin), same bank group	7.5ns	3C
46~59	Reserved	Reserved	00
60	Connector to SDRAM Bit Mapping		16
61	Connector to SDRAM Bit Mapping		36
62	Connector to SDRAM Bit Mapping		0B
63	Connector to SDRAM Bit Mapping		35
64	Connector to SDRAM Bit Mapping		16
65	Connector to SDRAM Bit Mapping		36
66	Connector to SDRAM Bit Mapping		0B
67	Connector to SDRAM Bit Mapping		35
68	Connector to SDRAM Bit Mapping		00
69	Connector to SDRAM Bit Mapping		00
70	Connector to SDRAM Bit Mapping		16
71	Connector to SDRAM Bit Mapping		36
72	Connector to SDRAM Bit Mapping		0B
73	Connector to SDRAM Bit Mapping		35
74	Connector to SDRAM Bit Mapping		16
75	Connector to SDRAM Bit Mapping		36
76	Connector to SDRAM Bit Mapping		0B
77	Connector to SDRAM Bit Mapping		35
78~116	Reserved	Reserved	00
117	Fine Offset for Minimum CAS to CAS Delay Time(tCCD_Lmin), same bank group	5.0ns	00
118	Fine Offset for Minimum Activate to Acticate Delay Time(tRRD_L_min), Same Bank Group	6.40ns	9C
119	Fine Offset for Minimum Activate to Acticate Delay Time(tRRD_Smin), Different Bank Group	5.30ns	B5
120	Fine Offset for Minimum Activate to Acticate/Refresh Delay Time(tRCmin)	45.75ns	00
121	Fine Offset for Minimum Row Precharge Delay Time(tRPmin)	13.75ns	00
122	Fine Offset for Minimum RAS to CAS Delay Time(tRCD_min)	13.75ns	00
123	Fine Offset for Minimum CAS Latency Delay Time(tAA_min)	13.75ns	00
124	Fine Offset for DRAM Maximum Cycle Time(tCKAVG_max)	1.6ns	E7
125	Fine Offset for DRAM Minimum Cycle Time(tCKAVG_min)	0.625ns	00
126	Cyclical Redundancy Code	-	64
127	Cyclical Redundancy Code	-	FD
128	Raw Card Extension, Module Nominal Height	30.00mm	0F
129	Module Maximum Thickness		11
130	Reference Raw Card Used	C0	02
131	Module Attributes	Standard	00
132	Reserved	Reserved	00
133	Reserved	Reserved	00
134	Reserved	Reserved	00
135	Reserved	Reserved	00
136	Reserved	Reserved	00
137	Reserved	Reserved	00

SPD Content(cont)

Byte	Function Described	Function Supported	Hex Value
138	Reserved	Reserved	00
139~253	Reserved	Reserved	00
254	Cyclical Redundancy Code	-	DB
255	Cyclical Redundancy Code	-	08
256~319	Reserved	Reserved	00
320	Module Manufacturer's ID Code, Least Significant Byte	Kingston	01
321	Module Manufacturer's ID Code, Most Significant Byte	Kingston	98
322	Module Manufacturing Location		00
323	Module Manufacturing Date	Variable	00
324	Module Manufacturing Date	Variable	00
325	Module Serial Number	-	00
326	Module Serial Number	-	00
327	Module Serial Number	-	00
328	Module Serial Number	-	00
329	Module Part Number	C	43
330	Module Part Number	B	42
331	Module Part Number	D	44
332	Module Part Number	3	33
333	Module Part Number	2	32
334	Module Part Number	D	44
335	Module Part Number	4	34
336	Module Part Number	S	53
337	Module Part Number	2	32
338	Module Part Number	S	53
339	Module Part Number	1	31
340	Module Part Number	M	4D
341	Module Part Number	E	45
342	Module Part Number	-	2D
343	Module Part Number	8	38
344	Module Part Number	Blank	20
345	Module Part Number	Blank	20
346	Module Part Number	Blank	20
347	Module Part Number	Blank	20
348	Module Part Number	Blank	20
349	Module Revision Code		00
350	DRAM Manufacturer's ID Code, Least Significant Byte	Micron	80
351	DRAM Manufacturer's ID Code, Most Significant Byte	Micron	2C
352	DRAM Stepping	E-die	45
353~381	Module Manufacturer's Specific Data	Reserved	00
382~383	Reserved	Reserved	00
384~511	End User Programmable	Reserved	00